

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
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ATTY DOCKET NO.

03500.017638

APPLICATION NO. N.Y.A./

Nat'l Stage of
PCT/JP2003/013074

APPLICANT

Shunichi Ishihara et al.

FILING DATE

October 10, 2003

GROUP

N.Y.A.

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MC/		2002/0009895 A1	01/24/02	Nishida	438	758	
/MC/		6,090,361	07/18/00	Baba et al.	423	350	
/MC/		5,455,430	10/03/95	Noguchi et al.	257	53	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/MC/	JP	10-98205	04/14/98	Japan			Abstract
/MC/	JP	5-36611	02/2/93	Japan			Abstract
/MC/	JP	10-324515	12/08/98	Japan			Abstract
/MC/	JP	2003-243675	08/29/03	Japan			Abstract
/MC/	EP	0 831 539 A2	03/25/98	Europe			
/MC/	EP	0 867 405 A1	09/30/98	Europe			

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

/MC/		R. Kishore et al., "Thin Film Solar Cells from Directionally Solidified Polycrystalline Silicon Doped with B, Al, Cu and C," <i>Conference Record of the 19th IEEE Photovoltaic Specialists Conference</i> , 1987, pages 1271-1274.					

EXAMINER

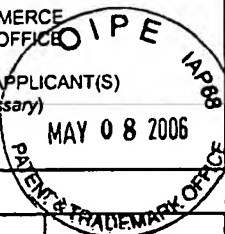
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07/27/2007

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Sheet 1 of 1

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PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)ATTY DOCKET NO.
03500.017636.APPLICATION NO.
10/530,189

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/MC/	6,953,506	10/11/05	Iwane, et al.	117	206	
	6,869,863	03/22/05	Nishida	438	497	
	6,824,609	11/30/04	Saito, et al.	117	54	
	6,818,911	11/16/04	Tamamori, et al.	250	492.22	
	6,818,104	11/16/04	Iwasaki, et al.	204	199	
	6,802,926	10/12/04	Mizutani, et al.	156	247	
	6,802,900	10/12/04	Iwane, et al.	117	54	
	6,756,289	06/29/04	Nakagawa, et al.	438	478	
	6,682,990	01/27/04	Iwane, et al.	438	458	
	6,664,169	12/16/03	Iwasaki, et al.	438	409	
	6,653,554	11/25/03	Ishihara	136	258	
	6,566,277	05/20/03	Nakagawa, et al.	438	761	
	6,566,235	05/20/03	Nishida, et al.	438	458	
	6,515,218	02/04/03	Shimizu, et al.	136	256	
	6,500,731	12/31/02	Nakagawa, et al.	438	455	

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/MC/	Haruo Itoh, et al., "Characterization of Silicon Layers Epitaxially Grown on Metallurgical-Grade Polycrystalline Substrates", Journal of Crystal Growth 45 (1978), pp. 446-453.
/MC/	T. H. Wang, et al., "Growth of silicon thin layers on cast MG-Si from metal solutions for solar cells", Solar Energy Materials and Solar Cells 41/42 (1996), pp. 19-30.

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/MC/	6,464,762	10/15/02	Arao	106	1.22	
	6,452,091	09/17/02	Nakagawa, et al.	136	261	
	6,429,035	08/06/02	Nakagawa, et al.	438	57	
	6,391,743	05/21/02	Iwane, et al.	438	458	
	6,387,780	05/14/02	Nishida, et al.	438	497	
	6,384,313	05/07/02	Nakagawa, et al.	136	244	
	6,331,208	12/18/01	Nishida, et al.	117	89	
	6,271,462	08/07/01	Tsuzuki, et al.	438	290	
	6,265,242	07/24/01	Komori, et al.	438	66	
	6,258,698	07/10/01	Iwasaki, et al.	438	455	
	6,258,666	07/10/01	Mizutani, et al.	438	258	
	6,248,948	06/19/01	Nakagawa, et al.	136	244	
	6,211,038	04/03/01	Nakagawa, et al.	438	409	
	6,190,937	02/20/01	Nakagawa, et al.	438	67	
	6,184,458	02/06/01	Murakami, et al.	136	256	
✓	6,180,868	01/30/01	Yoshino, et al.	136	244	

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. 03500.017636.		APPLICATION NO. 10/530,189	
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U.S. PATENT DOCUMENTS							
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/MC/		6,172,296	01/09/01	Iwasaki, et al.	136	256	
		6,162,986	12/19/00	Shiotsuka, et al.	136	244	
		6,140,209	10/31/00	Iwane, et al.	438	458	
		6,110,347	08/29/00	Arao, et al.	205	333	
		5,986,204	11/16/99	Iwasaki, et al.	136	256	
		5,981,864	11/09/99	Mizutani, et al.	136	244	
		5,770,463	06/23/98	Nakagawa, et al.	437	2	
		5,714,010	02/03/98	Matsuyama, et al.	118	723	
		5,712,199	01/27/98	Nakagawa, et al.	438	62	
		5,510,151	04/23/96	Matsuyama, et al.	427	509	
		5,486,238	01/23/96	Nakagawa, et al.	136	259	
		2005/0136576	06/23/05	Ishihara, et al.	438	162	
		2005/0109388	05/26/05	Murakami, et al.	136	255	
		2005/0087226	04/28/05	Nishida, et al.	438	256	
		2005/0066881	03/31/05	Nakagawa, et al.	117	18	
		2004/0118337	06/24/04	Mizutani, et al.	117	54	
		2004/0065251	04/08/04	Nishida, et al.	117	54	
✓		2002/0092464	07/18/02	Nakagawa, et al.	117	94	

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